

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination NOZAWA ET AL.	
		Examiner Gina M. Lupino	Art Unit 3652	Page 1 of 3

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,836,733	06-1989	Hertel et al.	414/744.5
*	B	US-6,315,512	11-2001	Tabrizi et al.	414/217
*	C	US-5,897,710	04-1999	Sato et al.	427/8
*	D	US-5,054,991	10-1991	Kato, Katsuhiko	414/783
*	E	US-4,887,904	12-1989	Nakazato et al.	356/621
*	F	US-5,483,138	01-1996	Shmookler et al.	318/568.16
*	G	US-6,142,722	11-2000	Genov et al.	414/217
*	H	US-4,955,780	09-1990	Shimane et al.	414/744.2
*	I	US-6,135,854	10-2000	Masumura et al.	451/6
*	J	US-6,516,244	02-2003	Yoo et al.	700/218
*	K	US-5,669,752	09-1997	Moon, Chang-youl	414/783
*	L	US-6,113,165	09-2000	Wen et al.	294/1.1
*	M	US-6,468,022	10-2002	Whitcomb, Preston	414/757

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited	Application/Control No.	Applicant(s)/Patent Under Reexamination	
	10/786,068	NOZAWA ET AL.	
Examiner Gina M. Lupino		Art Unit 3652	Page 2 of 3

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,206,441	03-2001	Wen et al.	294/1.1
*	B	US-6,327,517	12-2001	Sundar, Satish	700/245
*	C	US-6,502,054	12-2002	Mooring et al.	702/150
*	D	US-6,339,730	01-2002	Matsushima, Keiichi	700/218
*	E	US-6,478,532	11-2002	Coady et al.	414/783
*	F	US-6,162,008	12-2000	Perkins et al.	414/754
*	G	US-5,515,599	05-1996	Best, Norman D.	29/705
*	H	US-5,768,768	06-1998	Best, Norman D.	29/792
*	I	US-2002/0081175	06-2002	Kawahara et al.	414/217
*	J	US-2003/0018410	01-2003	Kretz et al.	700/218
*	K	US-2001/0000720	05-2001	Goodwin et al.	414/217
*	L	US-2002/0192056	12-2002	Reimer et al.	414/217
*	M	US-2001/0041122	11-2001	Kroeker, Tony	414/217

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	I					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination NOZAWA ET AL.	
		Examiner Gina M. Lupino	Art Unit 3652	Page 3 of 3

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0150447	10-2002	Mizokawa et al.	414/217
*	B	US-2002/0146304	10-2002	Yamashita et al.	414/217
*	C	US-6,502,054	12-2002	Mooring et al.	702/150
*	D	US-2002/0048502	04-2002	Minami et al.	414/217
*	E	US-2002/0111710	08-2002	Perlov et al.	700/229
*	F	US-2002/0061245	05-2002	Hasegawa et al.	414/217
*	G	US-2003/0021671	01-2003	Edo, Ryo	414/939
*	H	US-2003/0113187	06-2003	Lei et al.	414/217
*	I	US-2002/0031420	03-2002	KROEKER, TONY	414/217
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.